# Silicon P Channel Power MOS FET High Speed Power Switching

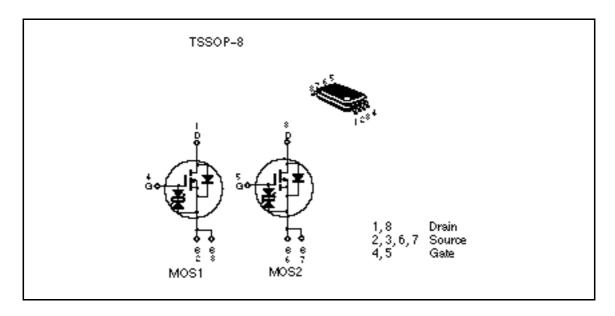
## HITACHI

ADE-208-528D (Z) 5th. Edition December 1998

#### **Features**

- Low on-resistance
- Capable of 2.5 V gate drive
- · Low drive current
- High density mounting

#### **Outline**





## **Absolute Maximum Ratings** $(Ta = 25^{\circ}C)$

| Item                                   | Symbol           | Ratings     | Unit |  |
|--|------------------|-------------|------|--|
| Drain to source voltage                | V <sub>DSS</sub> | -20         | V    |  |
| Gate to source voltage                 | V <sub>GSS</sub> | ±10         | V    |  |
| Drain current                          | I <sub>D</sub>   | -2.5        | A    |  |
| Drain peak current                     | I Note1          | -20         | A    |  |
| Body-drain diode reverse drain current | I <sub>DR</sub>  | -2.5        | A    |  |
| Channel dissipation                    | Pch Note2        | 1           | W    |  |
| Channel dissipation                    | Pch Note3        | 1.5         | W    |  |
| Channel temperature                    | Tch              | 150         | °C   |  |
| Storage temperature                    | Tstg             | -55 to +150 | °C   |  |

Note: 1. PW 10µs, duty cycle 1 %

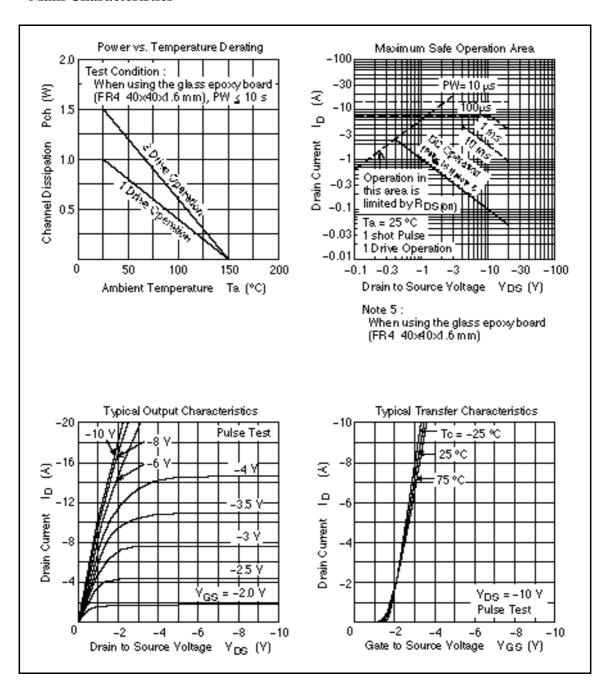
- 2. 1 Drive operation; When using the glass epoxy board (FR4 40 x 40 x 1.6 mm), PW 10s
- 3. 2 Drive operation; When using the glass epoxy board (FR4 40 x 40 x 1.6 mm), PW 10s

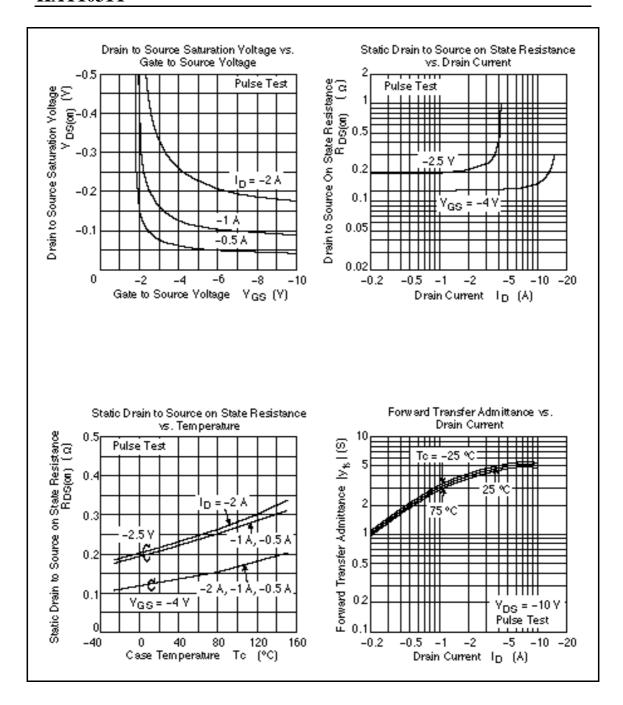
## **Electrical Characteristics** ( $Ta = 25^{\circ}C$ )

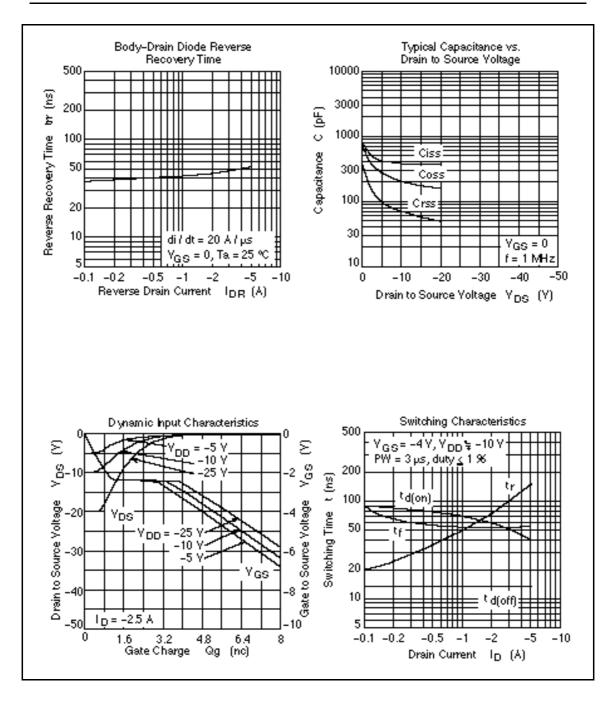
| Item                                   | Symbol               | Min  | Тур  | Max        | Unit | Test Conditions                                     |
|--|----------------------|------|------|------------|------|---|
| Drain to source breakdown voltage      | $V_{(BR)DSS}$        | -20  | _    | _          | V    | $I_{D} = -10 \text{mA}, V_{GS} = 0$                 |
| Gate to source breakdown voltage       | $V_{(BR)GSS}$        | ±10  | _    | _          | V    | $I_{G} = \pm 100 \mu A, V_{DS} = 0$                 |
| Gate to source leak current            | I <sub>GSS</sub>     | _    | _    | ±10        | μΑ   | $V_{GS} = \pm 8V$ , $V_{DS} = 0$                    |
| Zero gate voltege drain current        | I <sub>DSS</sub>     | _    | _    | <b>–</b> 1 | μΑ   | $V_{DS} = -20 \text{ V}, V_{GS} = 0$                |
| Gate to source cutoff voltage          | $V_{\text{GS(off)}}$ | -0.5 | _    | -1.5       | V    | $V_{DS} = -10V, I_{D} = -1mA$                       |
| Static drain to source on state        | R <sub>DS(on)</sub>  | _    | 0.13 | 0.16       |      | $I_{\rm D} = -2A, \ V_{\rm GS} = -4V^{\rm Note4}$   |
| resistance                             | R <sub>DS(on)</sub>  | _    | 0.21 | 0.28       |      | $I_{\rm D} = -2A, \ V_{\rm GS} = -2.5V^{\rm Note4}$ |
| Forward transfer admittance            | y <sub>fs</sub>      | 2.6  | 4    | _          | S    | $I_{\rm D} = -2A, \ V_{\rm DS} = -10V^{\rm Note4}$  |
| Input capacitance                      | Ciss                 | _    | 390  | _          | pF   | $V_{DS} = -10V$                                     |
| Output capacitance                     | Coss                 | _    | 200  | _          | pF   | $V_{GS} = 0$  |
| Reverse transfer capacitance           | Crss                 | _    | 70   | _          | pF   | f = 1MHz  |
| Turn-on delay time                     | t <sub>d(on)</sub>   | _    | 14   | _          | ns   | $V_{GS} = -4V, I_{D} = -2A$                         |
| Rise time                              | t <sub>r</sub>       | _    | 75   | _          | ns   | V <sub>DD</sub> -10V                                |
| Turn-off delay time                    | $t_{\text{d(off)}}$  | _    | 60   | _          | ns   | _   |
| Fall time                              | t <sub>f</sub>       | _    | 55   |            | ns   |   |
| Body-drain diode forward voltage       | $V_{DF}$             | _    | -0.9 | -1.17      | V    | $IF = -2.5A, V_{GS} = 0^{Note4}$                    |
| Body–drain diode reverse recovery time | t <sub>rr</sub>      | _    | 45   | _          | ns   | $IF = -2.5A, V_{GS} = 0$<br>diF/ dt =20A/µs         |

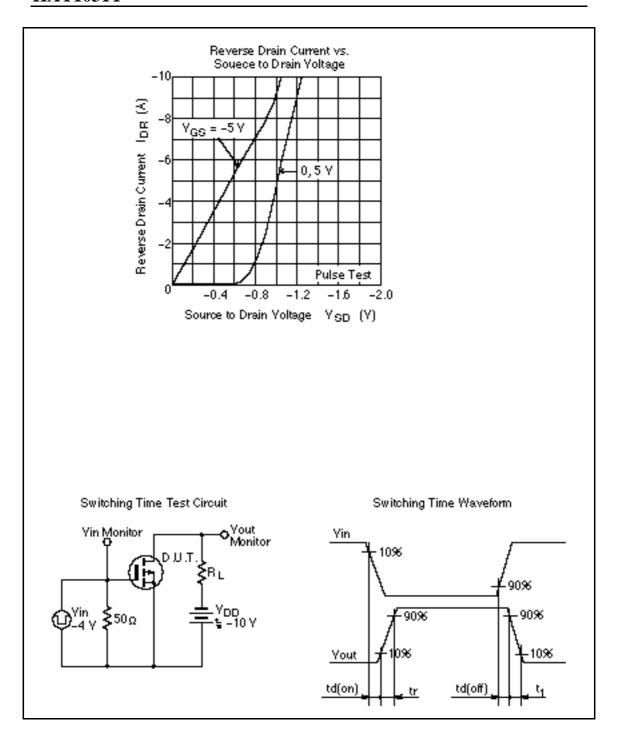
Note: 4. Pulse test

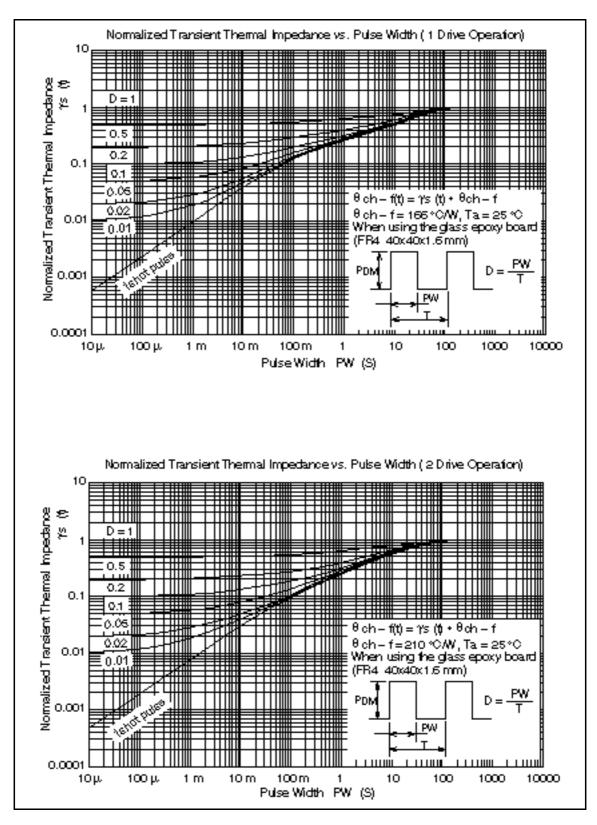
#### **Main Characteristics**





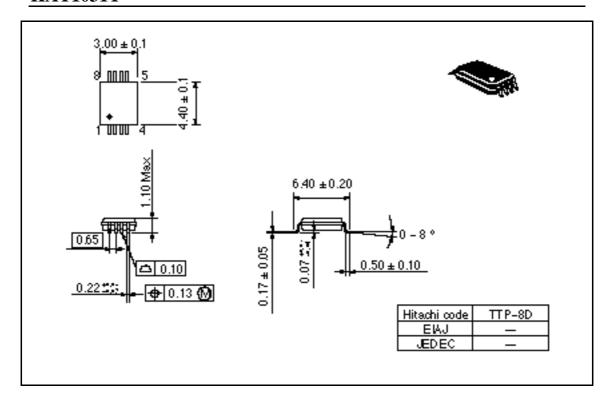






**Package Dimentions** 

Unit: mm



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